## SN5426, SN54LS26, SN7426, SN74LS26 QUADRUPLE 2-INPUT HIGH-VOLTAGE INTERFACE POSITIVE-NAND GATES

DECEMBER 1983-REVISED MARCH 1988

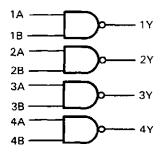
For Driving Low-Threshold-Voltage MOS Inputs

#### description

These 2-input open-collector NAND gates feature high-output voltage ratings for interfacing with low-threshold-voltage MOS logic circuits or other 12-volt systems. Although the output is rated to withstand 15 volts, the V<sub>CC</sub> terminal is connected to the standard 5-volt source.

The SN5426 and SN54LS26 are characterized for operation over the full military temperature range of  $-55\,^{\circ}\text{C}$  to 125 $\,^{\circ}\text{C}$ . The SN7426 and SN74LS26 are characterized for operation from  $0\,^{\circ}\text{C}$  to  $70\,^{\circ}\text{C}$ .

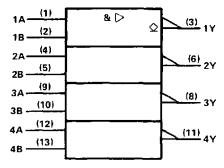
#### logic diagram



#### positive logic

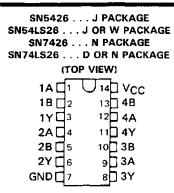
$$Y = \overline{AB}$$

#### logic symbol†

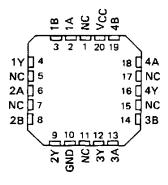


<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

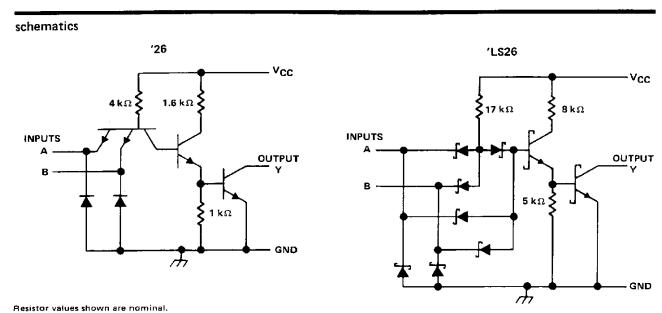


SN54LS26 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

## SN5426, SN54LS26, SNSN7426, SN74LS26 QUADRUPLE 2-INPUT HIGH-VOLTAGE INTERFACE POSITIVE-NAND GATES



Aesistor values shown are nominal.

### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage , VCC (see Note 1)
Input voltage: '26
'LS26 7 V
Operating free-air temperature: SN54'
SN74′
Storage temperature range

NOTE 1: Voltage values are with respect to network ground terminal.

#### recommended operating conditions

	SN54LS26			5			
	MIN	NOM	MAX	MIN	NOM	MAX	UNIT
V <sub>CC</sub> Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V <sub>IH</sub> High-level input voltage	2			2			V
VIL Low-level input voltage			0.7			0.8	V
VOH High-level output voltage			15			15	V
OL Law-level output current			4			8	mA
TA Operating free-air temperature	<b>–</b> 55		125	0		70	°C

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†			SN54LS26			S	26	UNIT	
	TEST CONDITIONS.		TIONS.	MIN	TYP‡	MAX	MIN	TYP‡	MAX	UNIT
VIK	V <sub>CC</sub> = MIN,	I <sub>1</sub> = 18 mA	<del> </del>			- 1.5			<b>– 1.5</b>	٧
юн	V <sub>CC</sub> = MIN,	VIL = MAX,	V <sub>OH</sub> = 12 V			50			50	μА
	V <sub>CC</sub> = MIN,	VIL = MAX,	V <sub>OH</sub> = 15 V			1			1	mA
	V <sub>CC</sub> = MIN,	V <sub>1H</sub> = 2 V,	I <sub>OL</sub> = 4 mA		0.25	0.4		0.25	0.4	
V <sub>O</sub> L	V <sub>CC</sub> = MIN,	V <sub>1H</sub> = 2 V,	IOL = 8 mA					0.35	0.5	٧
lį.	V <sub>CC</sub> = MAX,	V <sub>I</sub> = 7 V	<u> </u>			0.1			0.1	mΑ
ΊΗ	V <sub>CC</sub> = MAX,	V <sub>IH</sub> = 2.7 V				20			20	μΑ
HL	V <sub>CC</sub> = MAX,	V <sub>IL</sub> = 0.4 V	<u> </u>			- 0.4			- 0.4	mΑ
ГССН	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 0			0.8	1.6		8.0	1.6	mA
ICCL	V <sub>CC</sub> = MAX,	V <sub>I</sub> = 4.5 V			2.4	4.4		2,4	4.4	

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions, ‡ All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

## switching characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{C}$ (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN TYP	MAX	UNIT
tPLH .	A or B	<b>'</b>	$R_1 = 2 k\Omega$ , $C_1 = 15 pF$	17	32	ns
tpHL	7 31 15	<u>'</u>	1 11-2 Kis, C[-15 pr	15	28	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

## SN5426, SN7426 QUADRUPLE 2-INPUT HIGH-VOLTAGE INTERFACE POSITIVE-NAND GATES

#### recommended operating conditions

		SN5426			SN7426		
	MIN	NOM	MAX	MIN	NOM	MAX	UNIT
V <sub>CC</sub> Supply voltage	4.5	5	5.5	4.75	5	5.25	
VIH High-level input voltage	2			2			V
VIL Low-level input voltage			0.8			0.8	>
VOH High-level output voltage			15			15	>
IOL Low-level output current		-	16			16	mΑ
TA Operating free-air temperature	<b>–</b> 55		125	0		70	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	SN5426	\$N7426	Í
	TEST CONDITIONS.	MIN TYP# MAX	MIN TYP‡ MAX	UNIT
VIK	$V_{CC} = MIN, i_1 \approx -12 \text{ mA}$	- 1.5	-1.5	V
ЮН	$V_{CC} = MIN$ , $V_{IL} = 0.8 \text{ V}$ , $V_{OH} = 12 \text{ V}$		50	
	$V_{CC} = MIN$ , $V_{IL} = 0.7 \text{ V}$ , $V_{OH} = 12 \text{ V}$	50		μΑ
	VCC = MIN. VIL = 0.8 V, VOH = 15 V		1	
	$V_{CC} = MIN$ , $V_{IL} = 0.7 \text{ V}$ , $V_{OH} = 15 \text{ V}$	1		mA
VoL	$V_{CC} = MIN$ , $V_{IH} = 2 V$ , $I_{OL} = 16 mA$	0.4	0.4	V
lj .	V <sub>CC</sub> = MAX, V <sub>I</sub> = 5.5 V	1	1	mA
IH	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.4 V	40	40	μΑ
IL.	$V_{CC} = MAX$ , $V_{\parallel} = 0.4 \text{ V}$	-1.6	-1.6	mΑ
Іссн	$V_{CC} = MAX, V_I = 0$	4 8	4 8	mA
CCL	$V_{CC} = MAX$ , $V_I = 4.5 V$	12 22	12 22	mA

<sup>&</sup>lt;sup>†</sup>For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

## switching characteristics, VCC = 5 V, TA = 25°C (see note 2)

PAR	RAMETER	FROM (INPUT)	TQ (TUPTUO)	TEST CON	MIN	TYP	MAX	UNIT	
	<sup>t</sup> PLH	A or B	Y	R <sub>1</sub> = 1 kΩ,	C <sub>1</sub> = 15 pF		16	24	ns
	<sup>t</sup> PHL :				- 1 K32; CL = 15 pr		11	17	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

 $<sup>^{\</sup>ddagger}$ All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25 °C.

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